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Docket No.: 503.38097CX1

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1-8. (Canceled)
- 9. (New) A semiconductor device comprising:
 - a semiconductor substrate;
- a first electrode provided on a front plane of said semiconductor substrate, said first electrode containing an Al layer as a main component;
- a second electrode provided on a rear plane of said semiconductor substrate;
- a first metallic member disposed over said first electrode, said first metallic member being electrically connected to said first electrode;
- a second metallic member disposed under said second electrode, said second metallic member being electrically connected to said second electrode; and wherein a plurality of Au bumps are disposed between said first electrode and said first metallic member,
- wherein said first electrode, said Au bumps and said first metallic member are electrically connected.
- wherein said first metallic member is plated with a precious metal film, and
- wherein said front plane of said semiconductor substrate and each of said Au bumps are connected via an Au Al alloy layer.

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10. (New) A semiconductor device according to claim 9,

wherein said semiconductor substrate and parts of said first and second metallic members are covered by a resin body, and

wherein a bottom face of said second metallic member is exposed from said resin body.

11. (New) A semiconductor device according to claim 9,

wherein said first metallic member is comprised of a first portion and a second portion, said first portion is positioned over said first electrode and said second portion extends in direction from said first electrode to second electrode, and a bottom face of said second portion and a bottom face of said second metallic member are at a substantially same level.

- 12. (New) A semiconductor device according to claim 9, wherein sald semiconductor device is a surface mounting type device.
- 13. (New) A semiconductor device according to claim 9, wherein said precious metal film contains Pd.
- 14. (New) A semiconductor device according to claim 9, wherein each of said first and second metallic members contains a Cu core.

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- 15. (New) A semiconductor device according to claim 9,
 wherein said second electrode and second metallic member are
 connected via a Ag paste.
- 16. (New) A semiconductor device according to claim 9,
 wherein said semiconductor substrate includes a MOSFET,
 wherein said first electrode is electrically connected to a source region of
 said MOSFET, and

wherein said second electrode is electrically connected to a drain region of said MOSFET.

- 17. (New) A semiconductor device according to claim 9, wherein said semiconductor substrate is made of Si.
- 18. (New) A semiconductor device according to claim 9,
 wherein said semiconductor substrate and parts of said first and second
 metallic members are covered by a resin body,

wherein a bottom face of said second metallic member is exposed from said resin body, and

wherein said first metallic member is comprised of a first portion and a second portion, said first portion is positioned over said first electrode and said second portion extends in a direction from said first electrode to second electrode, and a bottom face of said second portion and a bottom face of said second metallic member are at a substantially same level.

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- 19. (New) A semiconductor device according to claim 18, wherein said semiconductor device is a surface mounting device.
- (New) A semiconductor device according to claim 18,
 wherein said precious metal film contains Pd.
- 21. (New) A semicondutor device according to claim 18,

 wherein each of said first and second metallic members contains a Cu
 core.
- 22. (New) A semiconductor device according to claim 18, wherein said second electrode and second metallic member are connected via a Ag paste.
- 23. (New) A semiconductor device according to claim 18,
 wherein said semiconductor substrate includes a MOSFET,
 wherein said first electrode is electrically connected to a source region of
 said MOSFET, and

wherein said second electrode is electrically connected to a drain region of said MOSFET.

24. (New) A semiconductor device according to claim 18, wherein said semiconductor substrate is made of Si.